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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

AKRAM ALI SALMAN  
XUEJUN ZHAO  
KURT O. TAYLOR  
STEPHEN G. BEEBE

Examiner: Laura M. Schillinger

Group Art Unit: 2813

Att'y Docket: 2000.111200/H2022

Customer No.: 23720

Serial No.: 10/664,665

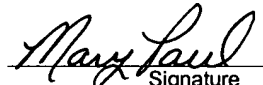
Filed: September 18, 2003

For: METHOD FOR DETERMINING THE  
RELIABILITY OF DIELECTRIC  
LAYERS

**RESPONSE TO FINAL OFFICE ACTION DATED JULY 12, 2005**

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

CERTIFICATE OF MAILING 37 C.F.R. 1.8	
I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date below:	
September 12, 2005 Date	 Signature

This paper is submitted in response to the Final Office Action dated July 12, 2005, for which the three-month date for response is October 12, 2005.

No fees are believed to be due in connection with the present paper. **However, should any fees be required under 37 C.F.R. §§ 1.16 to 1.21, the Director is authorized to deduct such fees from the Advanced Micro Devices, Inc. Deposit Account No. 01-0365/H2022. In the event the monies in that account are insufficient, the Director is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.111200.**

Reconsideration of the application in view of the following amendments and remarks is respectfully requested.